AMENDMENTS TO THE CLAIMS

Please cancel Claim 7.

1 (previously amended): A method for analyzing anisotropy of a sample comprising the steps of:

preparing two light beams having the same wavelength of which the plane of polarization are crossed at a given angle,

introducing the two light beams into a sample to be measured in anisotropy at the same time,

rotating the plane of polarization of one of the two light beams by the given angle so as to correspond to that of the other of the two light beams, after passing the two light beams through the sample,

superimposing the two light beams, and

observing an interference pattern of the thus obtained superimposed light beam to analyze anisotropy of the sample.

2 (previously amended): The method as defined in claim 1, wherein the given angle is 90 degrees.

3 (previously amended): The method as defined in claim 1, comprising the step of superimposing the two light beams before introducing into the sample, whereby the thus obtained superimposed light beam is introduced into the sample.

4 (previously amended): The method as defined in claim 3, wherein the given angle is 90 degrees.

5 (previously amended): The method as defined in claim 1, wherein the two light beams are introduced into the sample so that their beam directions are crossed.

6 (previously amended): The method as defined in claim 5, wherein the given angle is 90 degrees.

7 (canceled)

8 (previously amended): An apparatus for analyzing anisotropy of a sample comprising:

,before a sample to be measured in anisotropy,

a laser source to generate and oscillate a light beam to be used in anisotropy analysis,

a light beam-dividing means to divide a light beam from the laser source into two light beams, and

a first plane of polarization-rotating means to rotate the plane of polarization of one of the thus obtained two divided light beams by a given angle,

,after the sample to be measured in anisotropy,

a second plane of polarization-rotating means to rotate the plane of polarization of the one or the other of the two divided light beams by the given angle so that their planes of polarization can correspond each other,

a light beam-superimposing means to superimpose the two divided light beams, and

a light beam-projecting means to project and observe an interference pattern of the thus obtained superimposed light beam.

9 (previously amended): The apparatus as defined in claim 8, wherein at least one of the first and the second plane of polarization-rotating means is composed of a half-wave plate.

10 (previously amended): The apparatus as defined in claim 8, wherein at least one of the light beam-dividing means and the light beam-superimposing means is composed of a half mirror.

11 (previously amended): The apparatus as defined in claim 8, further comprising:

,before the sample to be measured in anisotropy, another light beam-superimposing means to superimpose the two divided light beams after the first plane of polarization-rotating means

,after the sample to be measured in anisotropy, a light beam-splitting means to split the superimposed light beam before the second plane of polarization-rotating means.

12 (previously amended): The apparatus as defined in claim 11, wherein at least one of the first and the second plane of polarization-rotating means is composed of a half-wave plate.

13 (previously amended): The apparatus as defined in claim 11, wherein at least one of the light beam-dividing means and the light beam-superimposing means is composed of a half mirror.

14 (previously amended): The apparatus as defined in claim 11, wherein the another light beam-superimposing means is composed of a half mirror.

15 (previously amended): The apparatus as defined in claim 11, wherein the light beam-splitting means is composed of a polarized light beam splitter.